



ESD



TVS



MOS



LDO



Diode



Sensor



DC-DC

Product Specification

▶ Domestic Part Number	EV-IRML6402-S1
▶ Overseas Part Number	IRML6402
▶ Equivalent Part Number	IRML6402

"S1" means SOT-23



EV is the abbreviation of name EVVO

-20V P-Channel Enhancement Mode MOSFET

Description

The EV-IRLML6402-S1 uses advanced trench technology to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Application

Advanced MOSFET process technology
Special designed for PWM, load switching and general purpose applications
Ultra low on-resistance with low gate charge
Fast switching and reverse body recovery
150°C operating temperature

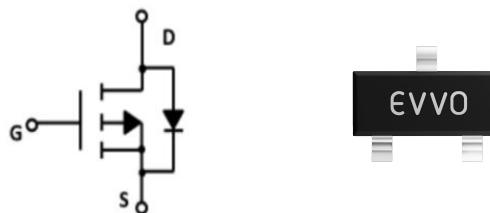
General Features

$V_{DS} = -20V, I_D = -4.2A$

$R_{DS(ON)} = 33m\Omega @ V_{GS}=4.5V$

$R_{DS(ON)} = 45m\Omega @ V_{GS}=2.5V$

SOT-23 Pin Configuration



Absolute max Rating: @ $T_A=25^\circ C$ unless otherwise specified

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-4 .2①	
$I_D @ T_C = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-2.4 ①	A
I_{DM}	Pulsed Drain Current ②	-30	
$P_D @ T_C = 25^\circ C$	Power Dissipation ③	1.4	W
V_{DS}	Drain-Source Voltage	-20	V
V_{GS}	Gate-to-Source Voltage	± 8	V
$T_J \ T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C
$R_{θJA}$	Junction-to-ambient ($t \leq 10s$) ④	90	°C /W

-20V P-Channel Enhancement Mode MOSFET
Electrical Characterizes @ $T_A=25^\circ C$ unless otherwise specified

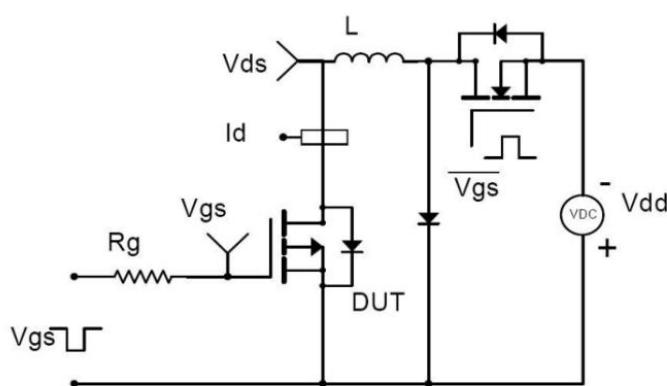
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-to-Source breakdown voltage	$V_{GS}=0V, I_D = -250\mu A$	-20	—	—	V
$R_{DS(on)}$	Static Drain-to-Source on-resistance	$V_{GS}=-4.5V, I_D = -4A$	—	33	35	$m\Omega$
		$V_{GS}=-2.5V, I_D = -4A$	—	45	54	
		$V_{GS}=-1.8V, I_D = -2A$	—	60	70	
VGS(th)	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	-0.3	—	-1.0	V
		$T_J = 125^\circ C$	—	-0.44	—	
IDSS	Drain-to-Source leakage current	$V_{DS} = -16V, V_{GS} = 0V$	—	—	-1	μA
		$T_J = 125^\circ C$	—	—	-50	
IGSS	Gate-to-Source forward leakage	$V_{GS} = 8V$	—	—	10	μA
		$V_{GS} = -8V$	—	—	-10	
Q_g	Total gate charge	$I_D = -4A,$ $V_{DS} = -10V,$ $V_{GS} = -4.5V$	—	10	—	nC
Q_{gs}	Gate-to-Source charge	—	—	0.77	—	
Q_{gd}	Gate-to-Drain("Miller") charge	—	—	3.5	—	
$t_{d(on)}$	Turn-on delay time	$V_{GS} = -4.5V, V_{DS} = -10V,$ $R_{GEN} = 3\Omega,$	—	10	—	
t_r	Rise time	—	—	8.6	—	ns
$t_{d(off)}$	Turn-Off delay time	—	—	29	—	
t_f	Fall time	—	—	13	—	
C_{iss}	Input capacitance	$V_{GS} = 0V, V_{DS} = -10V, f = 1MHz$	—	886.6	—	pF
C_{oss}	Output capacitance	—	—	140.6	—	
C_{rss}	Reverse transfer capacitance	—	—	129.2	—	

Notes:

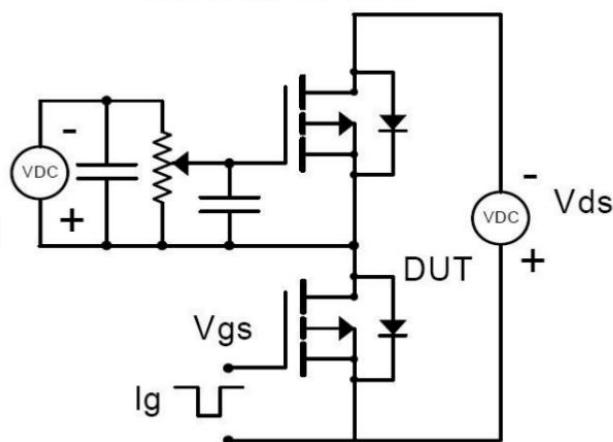
- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of R_{GJA} is measured with the device mounted on 1 in 2 FR 4 board with 2oz. Copper, in a still air environment with $TA = 25^\circ C$

-20V P-Channel Enhancement Mode MOSFET
Test circuits and Waveforms

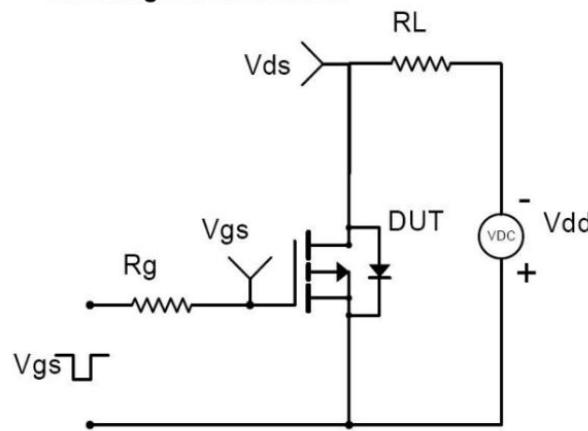
EAS test circuit:



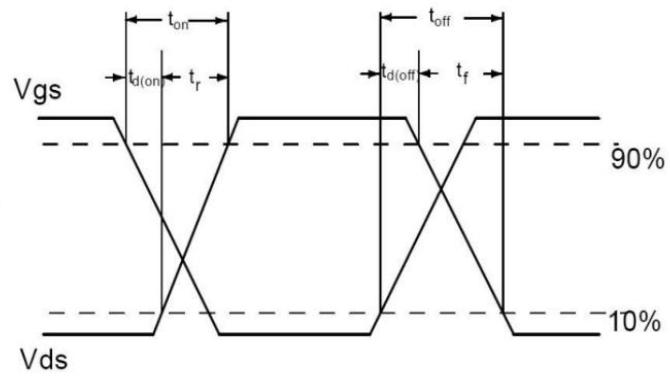
Gate charge test circuit:



Switching time test circuit:



Switch Waveforms:



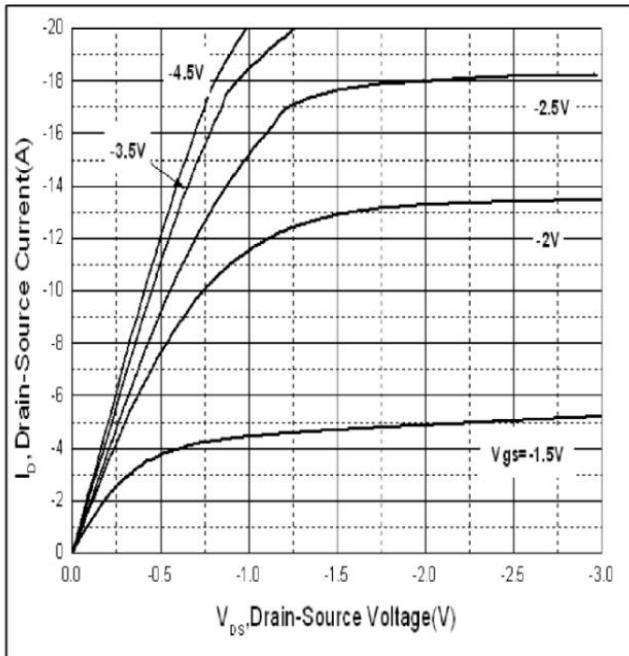
-20V P-Channel Enhancement Mode MOSFET
Typical electrical and thermal characteristics


Figure 1: Typical Output Characteristics

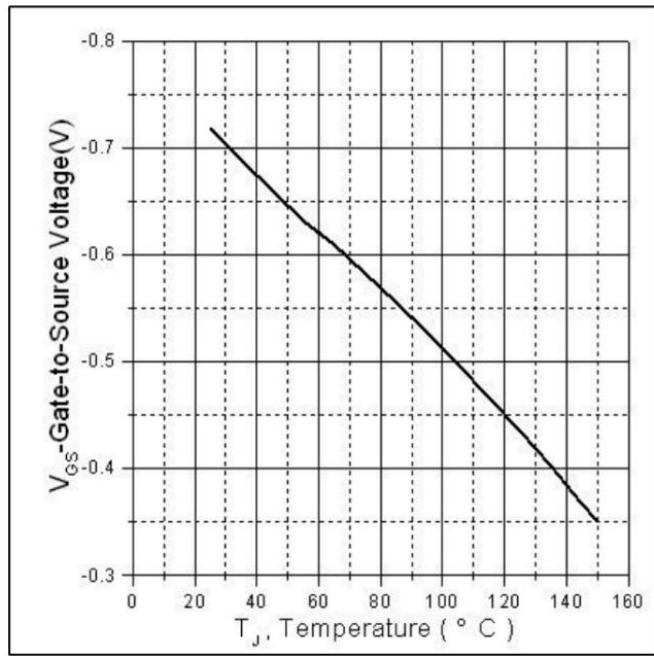


Figure 2. Gate to source cut-off voltage

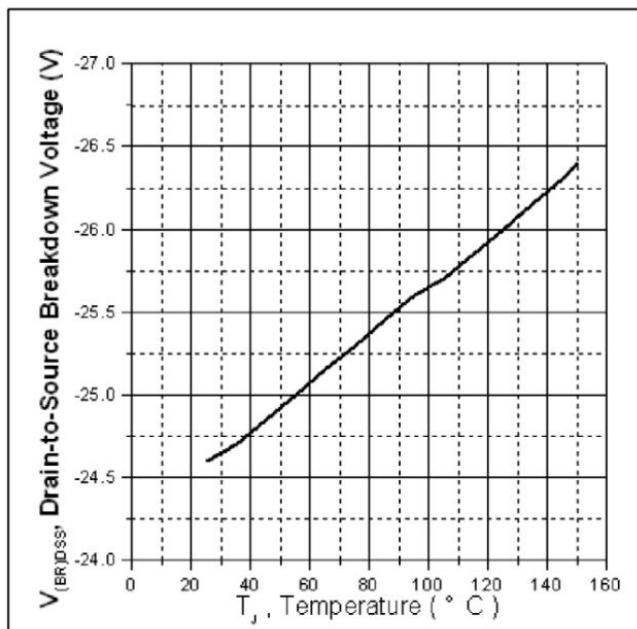


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

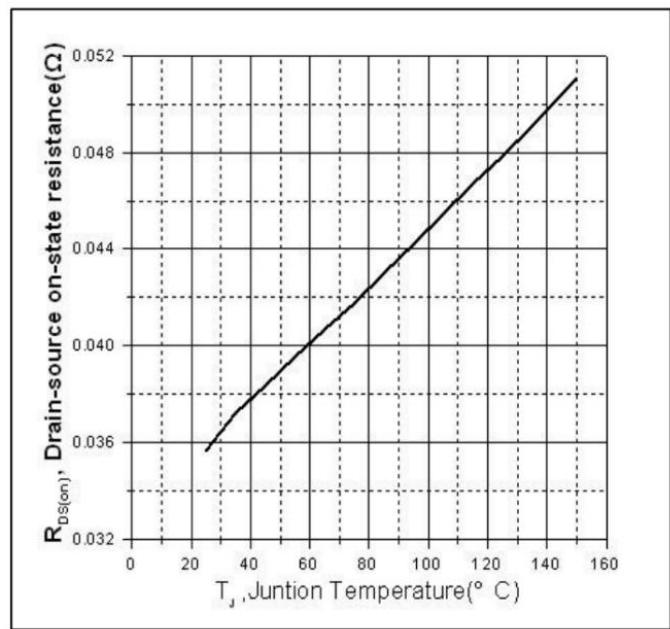


Figure 4: Normalized On-Resistance Vs. Case Temperature

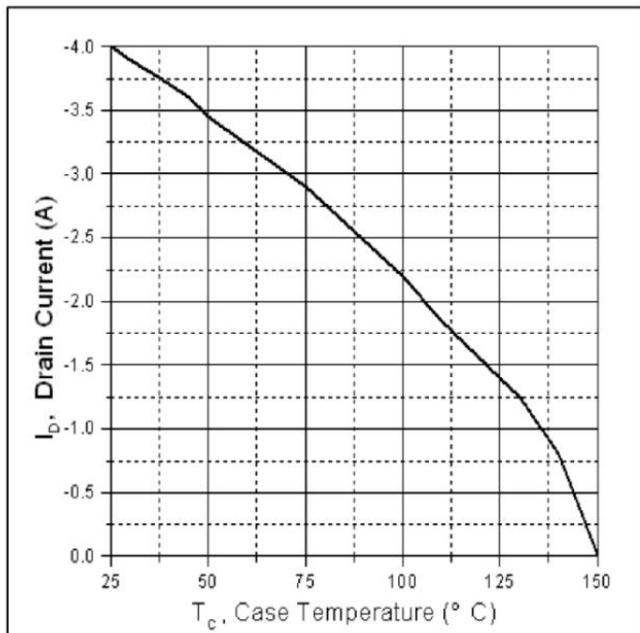
-20V P-Channel Enhancement Mode MOSFET
Typical electrical and thermal characteristics


Figure 5. Maximum Drain Current Vs. Case Temperature

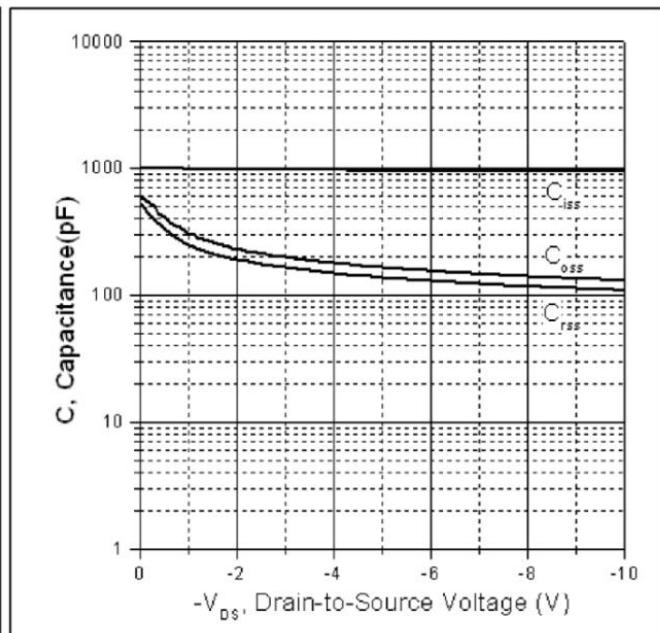


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

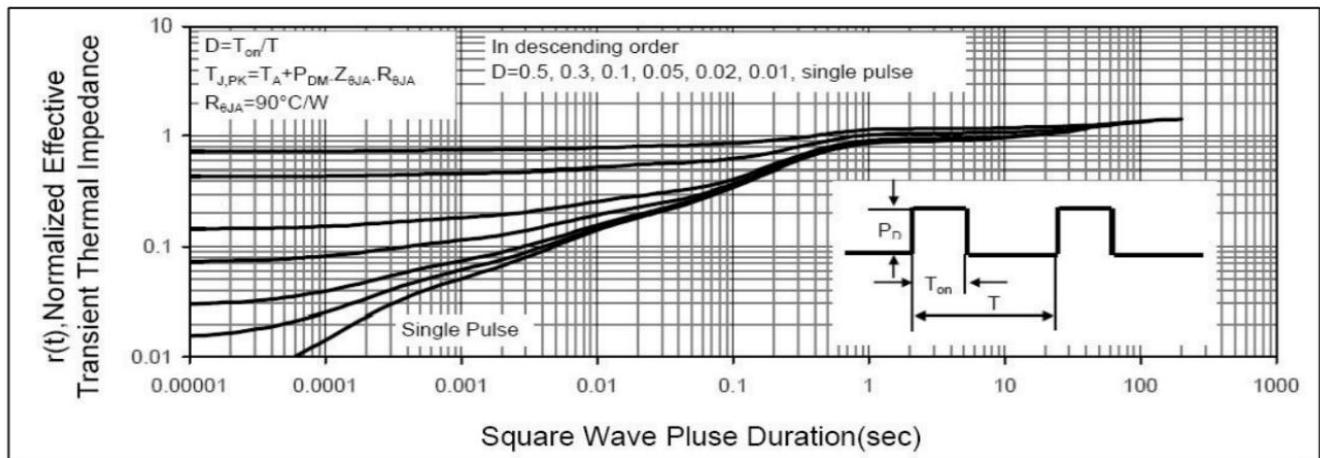
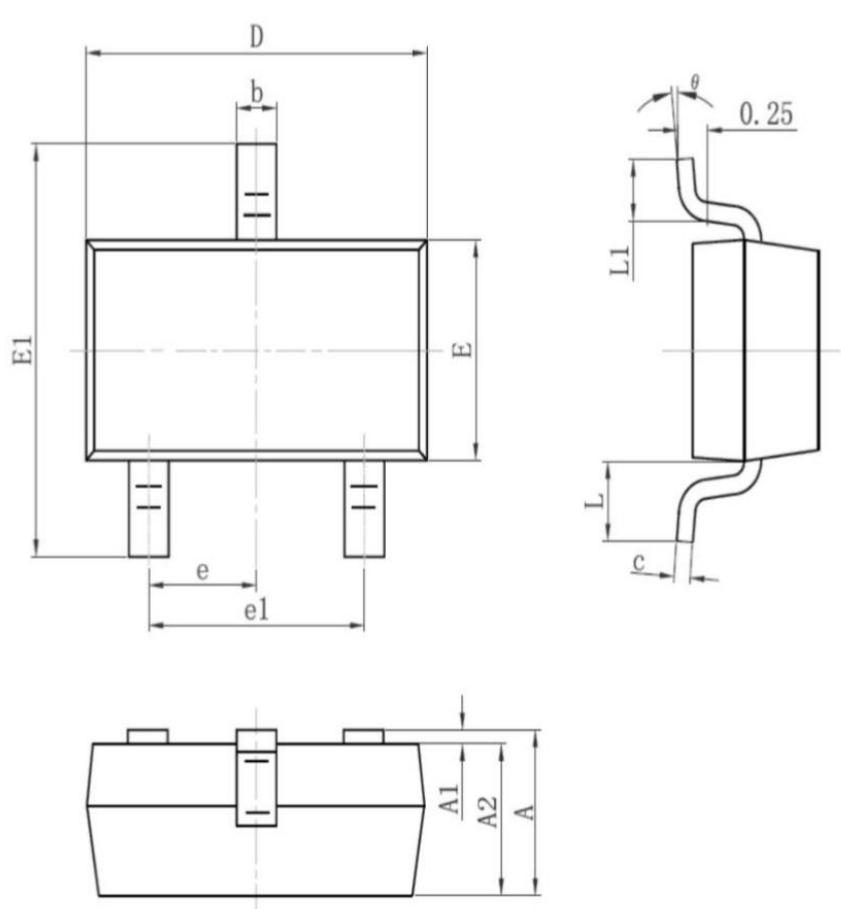


Figure 7. Maximum Effective Transient Thermal Impedance Junction-to-Case

-20V P-Channel Enhancement Mode MOSFET
Mechanical Data

SOT-23 PACKAGE OUTLINE DIMENSION



Symbol	Dimension In Millimeters		Dimension In Inches	
	Min	Max	Min	Max
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.95TYP		0.037TYP	
e1	1.800	2.000	0.071	0.079
L	0.55REF		0.022REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

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